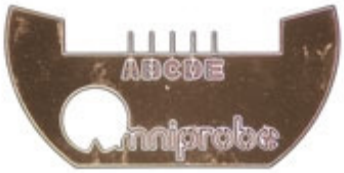
Omniprobe Nanomanipulation Systems

Omniprobe™ Half Grids A selection of high quality innovative supplies specially developed for FIB and SEM/FIB systems used for milling cross sections and TEM samples. Including a full range of consumables and accessories for the renowned Omniprobe Auto-Probe™ lift-out tools. Typical thickness of the grids is 25-30µm. The posts are designed for optimum access and provide a secure area for attaching (welding) the lamella(e). The Omniprobe® grids fit standard TEM holders and provide a non-obscured view of the thin sections attached to the posts.



5 post lift-out grids 3mm Ø specifically designed for in-situ lift-out. These grids include multiple indexed mounting locations, all with vertical bar attachment surfaces. Now with lower profile sides for easier access to outermost posts. Packaged in glassline envelopes.

G320 Omniprobe 5 post lift-out copper grid (100)

4 post lift-out grids 3mm Ø specifically designed for in-situ lift-out. These grids include multiple indexed mounting locations, two with vertical bar attachment surfaces and two with "V" shaped alignment surfaces. Sides have lower profile for easier access to outermost posts. Packaged in glassine envelopes.

G321 Omniprobe 4 post lift-out molybdenum grid (100)
G322 Omniprobe 4 post lift-out copper grid (100)

3 post lift-out grids 3mm Ø specifically designed for in-situ lift-out. These grids include multiple indexed mounting locations, two with vertical bar attachment surfaces and two with "V" shaped alignment surfaces. Sides have lower profile for easier access to outermost posts. Packaged in glassine envelopes.

G323 Omniprobe 3 post lift-out molybdenum grid (100)
G324 Omniprobe 3 post lift-out copper grid (100)
G325 Omniprobe 3 post lift-out copper grid, shallow downset and slightly wider centre post (100)

3 post lift-out grids 3mm Ø, 35µm thick with 1 edge lower for easy access. These grids include multiple indexed mounting locations, two with vertical bar attachment surfaces and two with "V" shaped alignment surfaces. Packaged in glass vials.

G326 Omniprobe 3 post lift-out copper grid with one lower edge (100)

Simple **Beryllium** half-ring grid

G327 Beryllium half-ring grid 3mm Ø

Storage box to hold 100 Omniprobe half grids or standard 3mm Ø TEM grids flat. No adhesive in tray (made from ABS). Cavity size is 3.34 x 3.34 x 1.5mm (0.13" x 0.13" x 0.06"). Complete with clear polystyrene lid and clear polypropylene clip. Stackable. Overall size is 55 x 51 x 10.7mm (2.16" x 2" x 0.42")

G328 Omniprobe grid box (1)

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Omniprobe Silicon Half Grids for in-situ FIB lift-out. 55º bevelled mounting flat for easy attachment.

G330

G331

G329 Omniprobe silicon lift-out grid 5º continuous mounted bevel surface (100)
G329/1 Omniprobe silicon lift-out grid 5º continuous mounted bevel surface (25)
G330 Omniprobe silicon lift-out grid with 4 sharp/shapeable mounting fingers (100)
G330/1 Omniprobe silicon lift-out grid with 4 sharp/shapeable mounting fingers (10)
G331 Omniprobe silicon lift-out grid with single mounting finger (100)
G331/1 Omniprobe silicon lift-out grid with single mounting finger (10)

Autoprobe™ Tip with Ni Shank for AutoProbe™ 100 & 200. Custom probe tip design for the AutoProbe™ 100 & 200 systems. Nickel tube shank with a diameter of 0.508mm (0.020") and a tungsten tip with a diameter of 76µm (0.003"). Tip radius is 0.5µm with a 13° taper angle for maximum lifetime. Nickel shank ~33.25mm (1.31") long. Tungsten tip ~35.5mm (1.40") with the tungsten whisker starting at 2.3mm (0.090") from the tip. The nickel shank is a magnetic material so not recommended for applications requiring high resolution imaging.

G332

G332 Tip with Ni shank for the Omniprobe AutoProbe™ 100 & 200 (10)

Autoprobe™ All W (Tungsten) tip design as provided with new systems. Tip radius of <0.5µm and a 7-10° taper angle for maximum lifetime. Shank diameter is 0.508mm (0.020"). Needle length is 34.036mm (1.340").

G333

G333 Standard W Tip for the Omniprobe AutoProbe™ 100 & 200 (10)

Autoprobe™ Tip narrow probe tips for the AutoProbe™ 100 and 200 systems. All Tungsten (W) design with dual taper angle. 7.8º to 6º with a tip radius of <0.5µm. Shank diameter is 0.508mm (0.020"). Needle length is 34.036mm (1.34"). The reduced taper angle allows for extended needle life for those users who cut and reshape their needles in the FIB.

G334

G334 Narrow W tip for the Omniprobe Autoprobe™ 100 & 200 (10)

Autoprobe™ Tip Custom etch design. In-situ probe tips. W (Tungsten) tip with stainless steel shank. Tip radius is 0.5µm with a 6° taper angle. For use with AutoProbe™ 300, in-situ probe tip exchange systems & Short-Cut™.

G335

G335 *in situ* probe tips for the Omniprobe AutoProbe™ 300 & 400 (20)

Autoprobe™ Tip in-situ W (Tungsten) needle with stainless steel shank custom etch design. Keyed with dual taper and flat on collar. 6° taper angle with a tip radius of 0.5um. Needle diameter is 0.254mm (0.010").

G336

G336 Keyed Probe tips for the Omniprobe AutoProbe™ 300 & 400 (20)

Autoprobe™ Tip in-situ W (Tungsten) needle with stainless steel shank low profile design. Keyed with dual taper and flat on shank. 6° taper angle with a tip radius of 0.5um. Needle diameter is 0.254mm (0.010"). For use with FEI Helios port systems.

G337

G337 Omniprobe AutoProbe™ 300 & 400 Probe Tips for FEI Helios Front Port (20)

Autoprobe™ Tip Custom keyed probe tips for the Omniprobe AutoProbe™ 300/400 systems with a flat on the reduced collar diameter to accommodate the 50º elevation angle on the FEI Helios front port systems. Tungsten tip with stainless steel shank, flat on smaller collar, tip radius is 0.5µm with an 8-10° taper angle.

G338

G338 Keyed Omniprobe AutoProbe™ 300 & 400 Probe Tips for the FEI Helios Front Port (20)